

Search Notes

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Examiner

Nam Huynh

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	458	5/16/2006	NTH
	403		
	422.1		
	456.2		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search notes.	5/16/2006	NTH